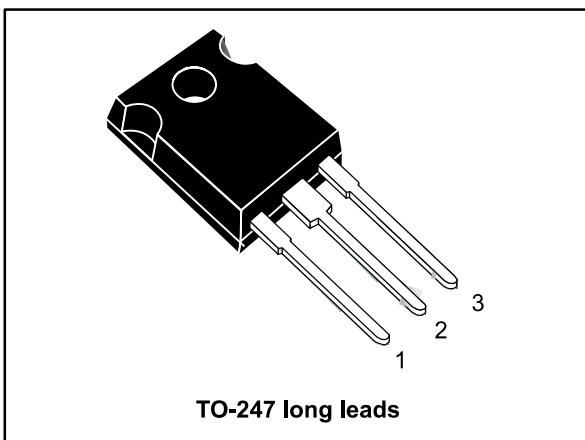
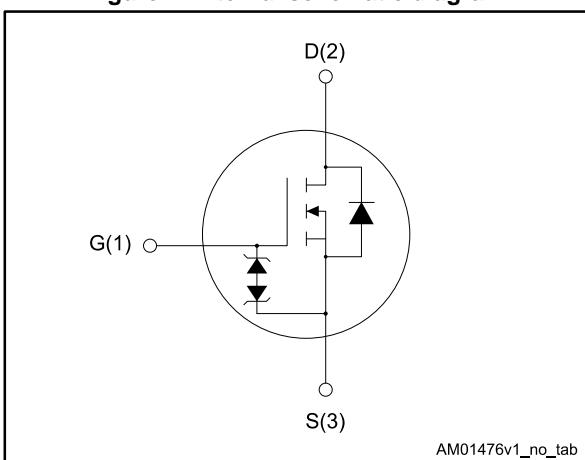


## N-channel 600 V, 0.06 Ω typ., 42 A MDmesh™ M2 Power MOSFET in a TO-247 long leads package

Datasheet - production data



**Figure 1: Internal schematic diagram**



### Features

Order code	V <sub>DS</sub> @ T <sub>Jmax</sub>	R <sub>D(on)</sub> max	I <sub>D</sub>
STWA48N60M2	650 V	0.07 Ω	42 A

- Extremely low gate charge
- Excellent output capacitance (C<sub>oss</sub>) profile
- 100% avalanche tested
- Zener-protected

### Applications

- Switching applications

### Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

**Table 1: Device summary**

Order code	Marking	Package	Packaging
STWA48N60M2	48N60M2	TO-247 long leads	Tube

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# 1 Electrical ratings

**Table 2: Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	42	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	26	A
$I_{DM}^{(1)}$	Drain current (pulsed)	168	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	300	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(3)}$	MOSFET dv/dt ruggedness	50	V/ns
$T_{stg}$	Storage temperature	- 55 to 150	$^\circ\text{C}$
$T_j$	Operating junction temperature		

**Notes:**

(1) Pulse width limited by safe operating area.

(2)  $I_{SD} \leq 42$  A,  $di/dt \leq 400$  A/ $\mu\text{s}$ ;  $V_{DSpeak} < V_{(BR)DSS}$ ,  $V_{DD}=400$  V.(3)  $V_{DS} \leq 480$  V**Table 3: Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	0.42	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	50	$^\circ\text{C}/\text{W}$

**Table 4: Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )	7	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j=25^\circ\text{C}$ , $I_D=I_{AR}$ ; $V_{DD}=50$ )	4500	mJ

## 2 Electrical characteristics

( $T_C = 25^\circ\text{C}$  unless otherwise specified)

**Table 5: On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0$ , $I_D = 1 \text{ mA}$	600			V
$I_{\text{DS}}^{\text{SS}}$	Zero gate voltage drain current	$V_{GS} = 0$ , $V_{DS} = 600 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0$ , $V_{DS} = 600 \text{ V}$ , $T_C = 125^\circ\text{C}$			100	$\mu\text{A}$
$I_{G\text{SS}}$	Gate-body leakage current	$V_{DS} = 0$ , $V_{GS} = \pm 25 \text{ V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}$ , $I_D = 21 \text{ A}$		0.06	0.07	$\Omega$

**Table 6: Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{GS} = 0$ , $V_{DS} = 100 \text{ V}$ , $f = 1 \text{ MHz}$ ,	-	3060	-	pF
$C_{oss}$	Output capacitance		-	143	-	pF
$C_{rss}$	Reverse transfer capacitance		-	4.3	-	pF
$C_{oss \text{ eq. } (1)}$	Equivalent output capacitance	$V_{GS} = 0$ , $V_{DS} = 0$ to $480 \text{ V}$	-	630	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}$ , $I_D = 0$	-	4.6	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480 \text{ V}$ , $I_D = 42 \text{ A}$ , $V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 15: "Test circuit for gate charge behavior"</a> )	-	70	-	nC
$Q_{gs}$	Gate-source charge		-	10.5	-	nC
$Q_{gd}$	Gate-drain charge		-	31	-	nC

**Notes:**

<sup>(1)</sup> $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 7: Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}$ , $I_D = 21 \text{ A}$ , $R_G = 4.7 \Omega$ , $V_{GS} = 10 \text{ V}$	-	18.5	-	ns
$t_r$	Rise time		-	17	-	ns
$t_{d(off)}$	Turn-off-delay time	(see <a href="#">Figure 14: "Test circuit for resistive load switching times"</a> )	-	13	-	ns
$t_f$	Fall time		-	119	-	ns

Table 8: Source drain diode

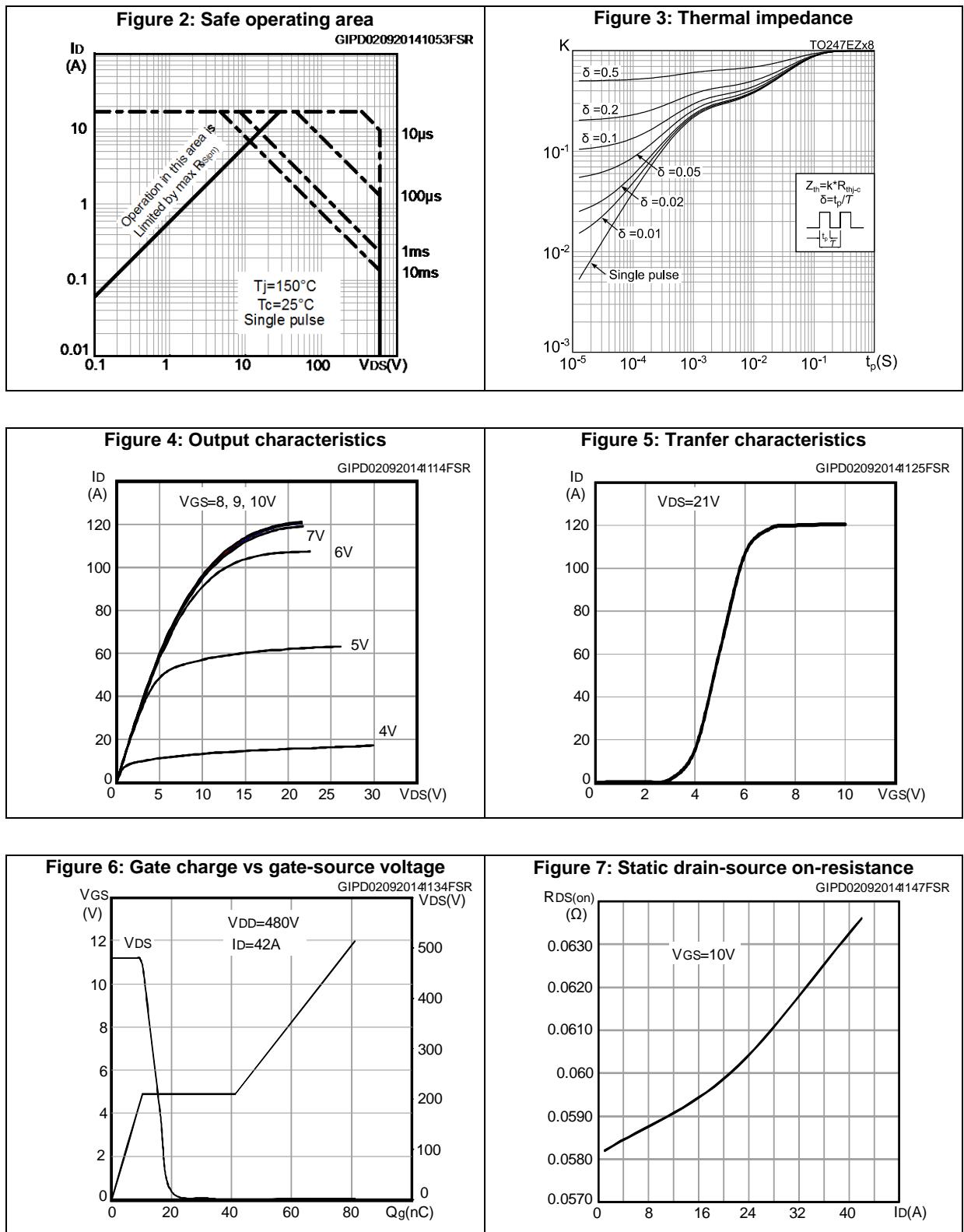
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		42	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		168	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0$ , $I_{SD} = 21$ A	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 42$ A, $dI/dt = 100$ A/ $\mu$ s $V_{DD} = 60$ V (see <i>Figure 17: "Unclamped inductive load test circuit"</i> )	-	487		ns
$Q_{rr}$	Reverse recovery charge		-	9.1		$\mu$ C
$I_{RRM}$	Reverse recovery current		-	37.5		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 42$ A, $dI/dt = 100$ A/ $\mu$ s $V_{DD} = 60$ V, $T_j = 150$ °C (see <i>Figure 17: "Unclamped inductive load test circuit"</i> )	-	605		ns
$Q_{rr}$	Reverse recovery charge		-	12.5		$\mu$ C
$I_{RRM}$	Reverse recovery current		-	41.5		A

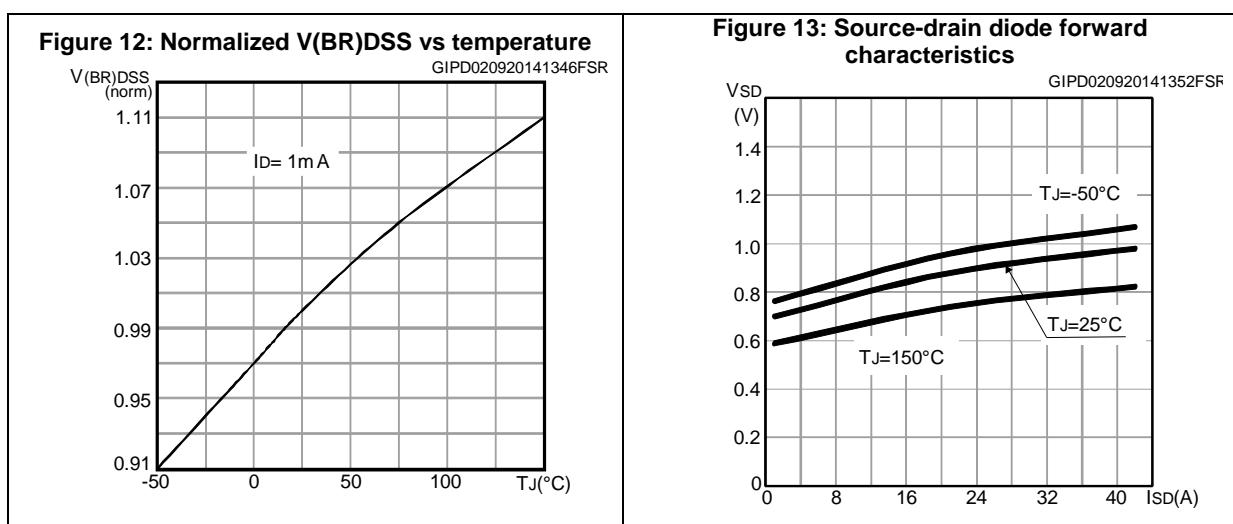
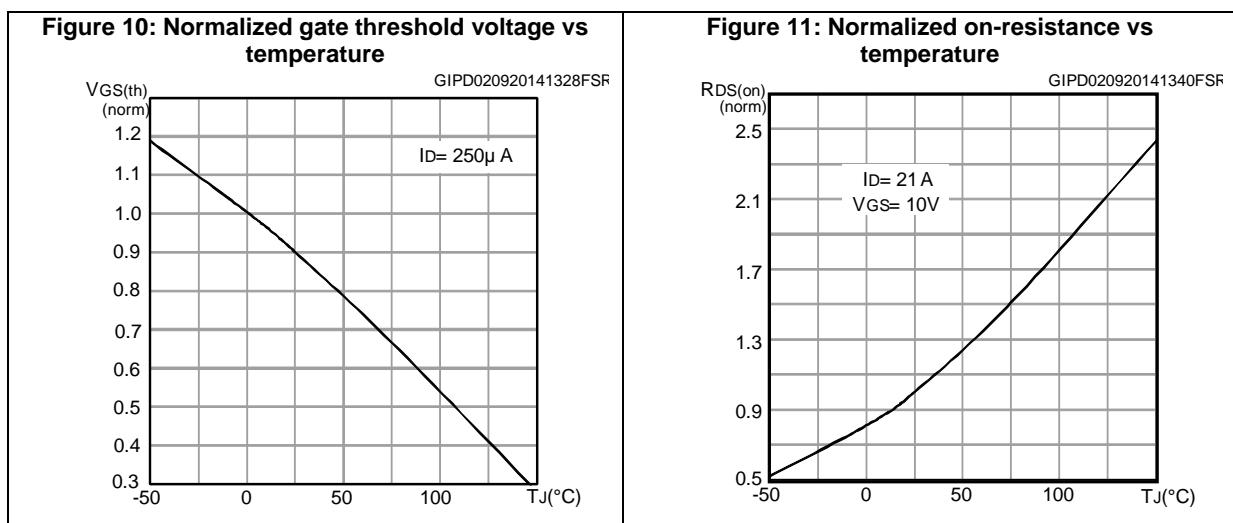
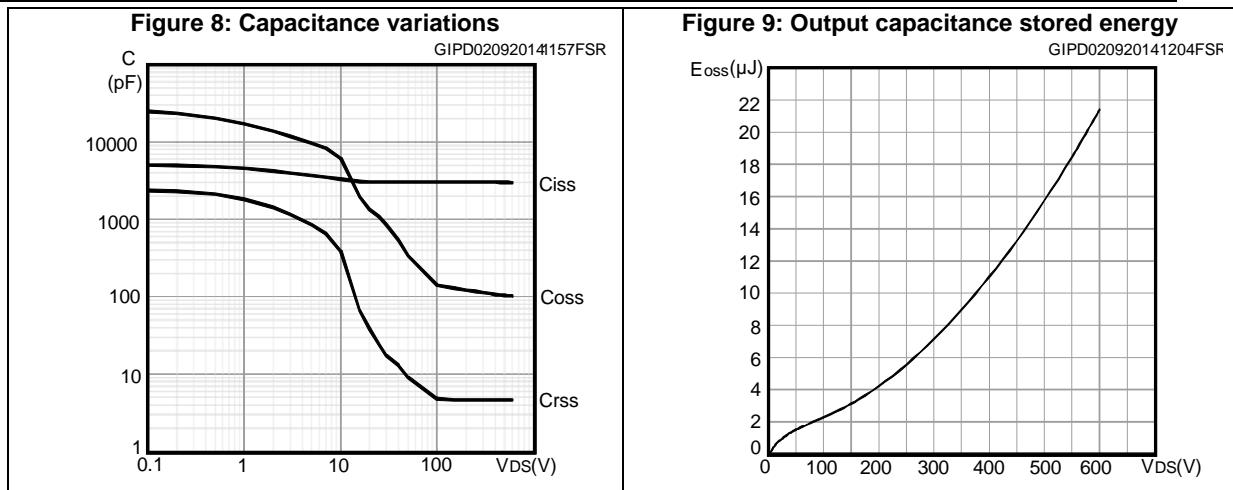
**Notes:**

(1)Pulse width limited by safe operating area.

(2)Pulsed: pulse duration = 300  $\mu$ s, duty cycle 1.5%

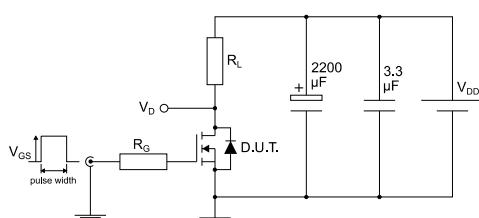
## 2.1 Electrical characteristics (curves)



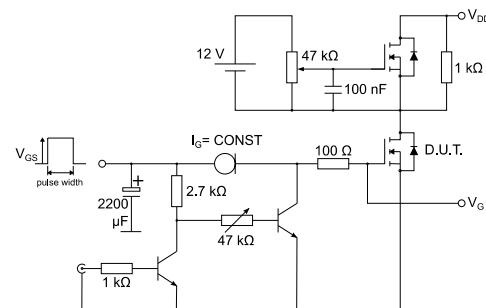


### 3 Test circuits

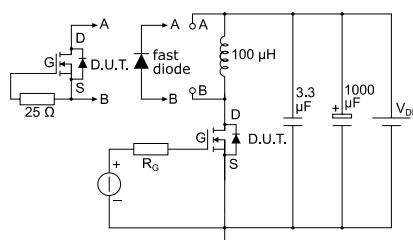
**Figure 14: Test circuit for resistive load switching times**



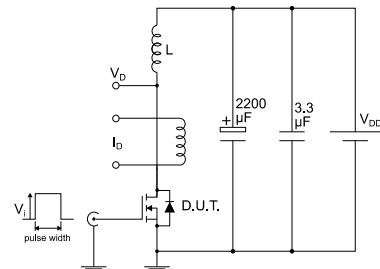
**Figure 15: Test circuit for gate charge behavior**



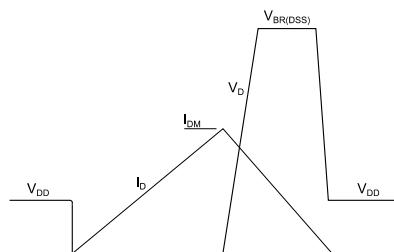
**Figure 16: Test circuit for inductive load switching and diode recovery times**



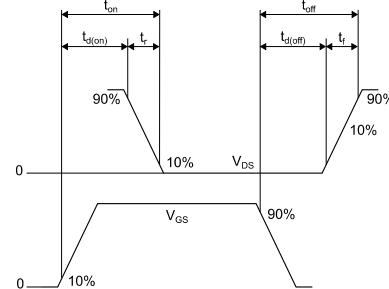
**Figure 17: Unclamped inductive load test circuit**



**Figure 18: Unclamped inductive waveform**



**Figure 19: Switching time waveform**



## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK is an ST trademark.

### 4.1 TO-247 long leads package information

Figure 20: TO-247 long leads package outline

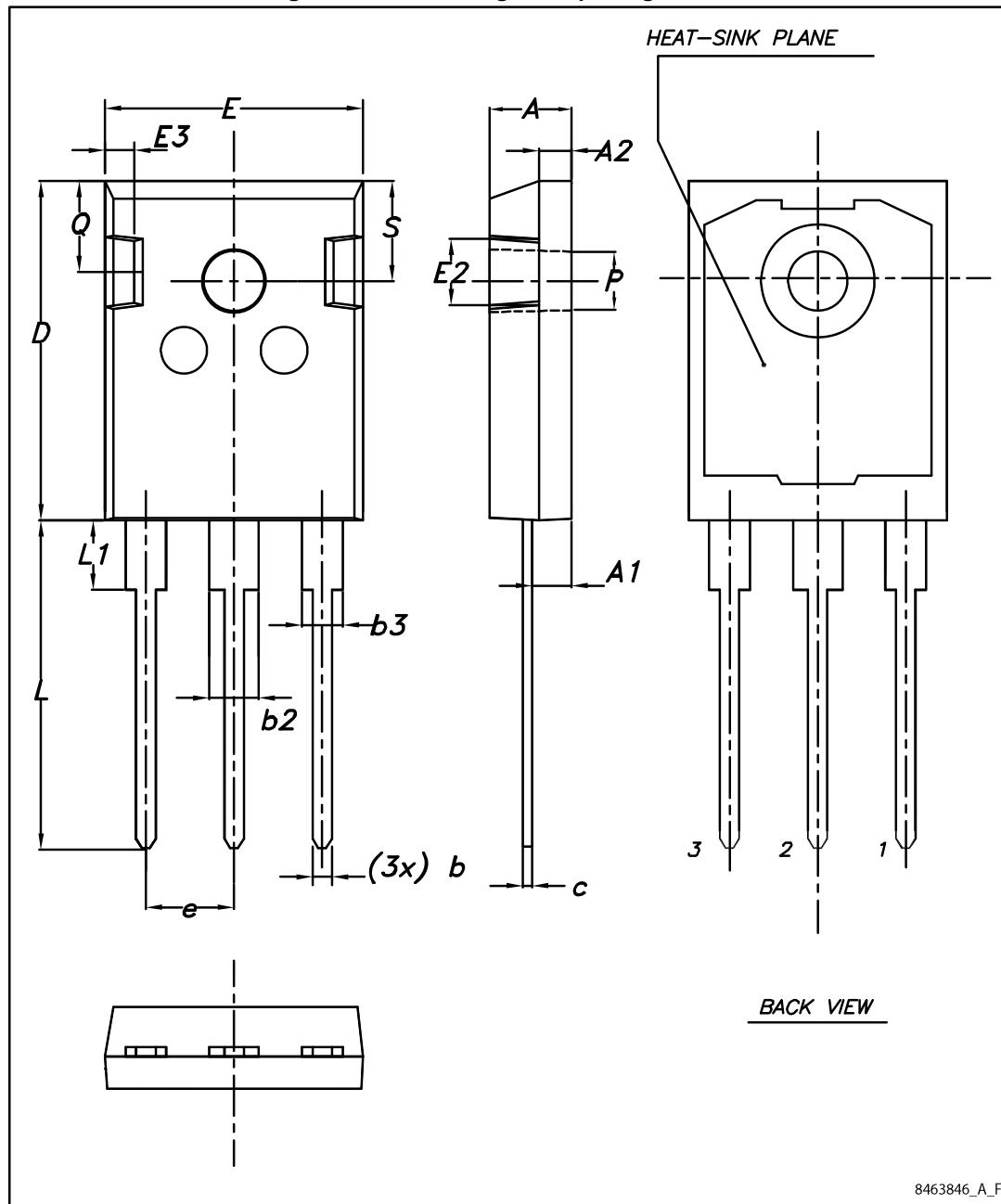


Table 9: TO-247 long leads package mechanical data

Dim.	mm.		
	Min.	Typ.	Max.
A	4.90	5.00	5.10
A1	2.31	2.41	2.51
A2	1.90	2.00	2.10
b	1.16		1.26
b2			3.25
b3			2.25
c	0.59		0.66
D	20.90	21.00	21.10
E	15.70	15.80	15.90
E2	4.90	5.00	5.10
E3	2.40	2.50	2.60
e	5.34	5.44	5.54
L	19.80	19.92	20.10
L1			4.30
P	3.50	3.60	3.70
Q	5.60		6.00
S	6.05	6.15	6.25

## 5 Revision history

Table 10: Document revision history

Date	Revision	Changes
01-Dec-2015	1	First release.

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